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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	HCS12
Core Size	16-Bit
Speed	25MHz
Connectivity	CANbus, I²C, SCI, SPI
Peripherals	PWM, WDT
Number of I/O	91
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	2.35V ~ 5.25V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	112-LQFP
Supplier Device Package	112-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s12db128bcpv

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1.4 Block Diagram

Figure 1-1 shows a block diagram of the MC9S12DT128B device.

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$00A0 - $00C7 PWM (Pulse Width Modulator 8 Bit 8 Channel)

Address	Name		Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
$00C2	PWMDTY6	Read: Write:	Bit 7	6	5	4	3	2	1	Bit 0
$00C3	PWMDTY7	Read: Write:	Bit 7	6	5	4	3	2	1	Bit 0
$00C4	PWMSDN	Read: Write:	PWMIF	PWMIE	PWMRSTRT	PWMLVL	0	PWM7IN	PWM7INL	PWM7ENA
$00C5	Reserved	Read: Write:	0	0	0	0	0	0	0	0
$00C6	Reserved	Read: Write:	0	0	0	0	0	0	0	0
$00C7	Reserved	Read: Write:	0	0	0	0	0	0	0	0

$00C8 - $00CF SCI0 (Asynchronous Serial Interface)

Address	Name		Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
$00C8	SCI0BDH	Read: Write:	0	0	0	SBR12	SBR11	SBR10	SBR9	SBR8
$00C9	SCI0BDL	Read: Write:	SBR7	SBR6	SBR5	SBR4	SBR3	SBR2	SBR1	SBR0
$00CA	SCI0CR1	Read: Write:	LOOPS	SCISWAI	RSRC	M	WAKE	ILT	PE	PT
$00CB	SCI0CR2	Read: Write:	TIE	TCIE	RIE	ILIE	TE	RE	RWU	SBK
$00CC	SCI0SR1	Read: Write:	TDRE	TC	RDRF	IDLE	OR	NF	FE	PF
$00CD	SCI0SR2	Read: Write:	0	0	0	0	0	BRK13	TXDIR	RAF
$00CE	SCI0DRH	Read: Write:	R8	T8	0	0	0	0	0	0
$00CF	SCI0DRL	Read: Write:	R7	R6	R5	R4	R3	R2	R1	R0
			T7	T6	T5	T4	T3	T2	T1	T0

$00D0 - $00D7 SCI1 (Asynchronous Serial Interface)

Address	Name		Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
$00D0	SCI1BDH	Read: Write:	0	0	0	SBR12	SBR11	SBR10	SBR9	SBR8
$00D1	SCI1BDL	Read: Write:	SBR7	SBR6	SBR5	SBR4	SBR3	SBR2	SBR1	SBR0
$00D2	SCI1CR1	Read: Write:	LOOPS	SCISWAI	RSRC	M	WAKE	ILT	PE	PT
$00D3	SCI1CR2	Read: Write:	TIE	TCIE	RIE	ILIE	TE	RE	RWU	SBK
$00D4	SCI1SR1	Read: Write:	TDRE	TC	RDRF	IDLE	OR	NF	FE	PF

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$0100 - $010F Flash Control Register (fts128k2)

Address	Name		Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
$0100	FCLKDIV	Read:	FDIVLD	PRDIV8	FDIV5	FDIV4	FDIV3	FDIV2	FDIV1	FDIV0
		Write:								
$0101	FSEC	Read:	KEYEN	NV6	NV5	NV4	NV3	NV2	SEC1	SEC0
		Write:								
$0102	FTSTMOD	Read:	0	0	0	WRALL	0	0	0	0
		Write:								
$0103	FCNFG	Read:	CBEIE	CCIE	KEYACC	0	0	0	BKSEL1	BKSEL0
		Write:								
$0104	FPROT	Read:	FPOPEN	NV6	FPHDIS	FPHS1	FPHS0	FPLDIS	FPLS1	FPLS0
		Write:								
$0105	FSTAT	Read:	CBEIF	CCIF	PVIOL	ACCERR	0	BLANK	0	0
		Write:								
$0106	FCMD	Read:	0	CMDB6	CMDB5	0	0	CMDB2	0	CMDB0
		Write:								
$0107	Reserved for Factory Test	Read:	0	0	0	0	0	0	0	0
		Write:								
$0108	FADDRHI	Read:	0	Bit 14	13	12	11	10	9	Bit 8
		Write:								
$0109	FADDRLO	Read:	Bit 7	6	5	4	3	2	1	Bit 0
		Write:								
$010A	FDATAHI	Read:	Bit 15	14	13	12	11	10	9	Bit 8
		Write:								
$010B	FDATALO	Read:	Bit 7	6	5	4	3	2	1	Bit 0
		Write:								
$010C - $010F	Reserved	Read:	0	0	0	0	0	0	0	0
		Write:								

$0110 - $011B EEPROM Control Register (eets2k)

Address	Name		Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
$0110	ECLKDIV	Read:	EDIVLD	PRDIV8	EDIV5	EDIV4	EDIV3	EDIV2	EDIV1	EDIV0
		Write:								
$0111	Reserved	Read:	0	0	0	0	0	0	0	0
		Write:								
$0112	Reserved for Factory Test	Read:	0	0	0	0	0	0	0	0
		Write:								
$0113	ECNFG	Read:	CBEIE	CCIE	0	0	0	0	0	0
		Write:								
$0114	EPROT	Read:	EPOPEN	NV6	NV5	NV4	EPDIS	EP2	EP1	EP0
		Write:								
$0115	ESTAT	Read:	CBEIF	CCIF	PVIOL	ACCERR	0	BLANK	0	0
		Write:								
$0116	ECMD	Read:	0	CMDB6	CMDB5	0	0	CMDB2	0	CMDB0
		Write:								
$0117	Reserved for Factory Test	Read:	0	0	0	0	0	0	0	0
		Write:								
$0118	EADDRHI	Read:	0	0	0	0	0	0	Bit 9	Bit 8
		Write:								

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2.3 Detailed Signal Descriptions

2.3.1 EXTAL, XTAL — Oscillator Pins

EXTAL and XTAL are the crystal driver and external clock pins. On reset all the device clocks are derived from the EXTAL input frequency. XTAL is the crystal output.

2.3.2 $\overline{\text{RESET}}$ — External Reset Pin

An active low bidirectional control signal, it acts as an input to initialize the MCU to a known start-up state, and an output when an internal MCU function causes a reset.

2.3.3 TEST — Test Pin

This input only pin is reserved for test.

NOTE: *The TEST pin must be tied to VSS in all applications.*

2.3.4 XFC — PLL Loop Filter Pin

PLL loop filter. Please ask your Motorola representative for the interactive application note to compute PLL loop filter elements. Any current leakage on this pin must be avoided.

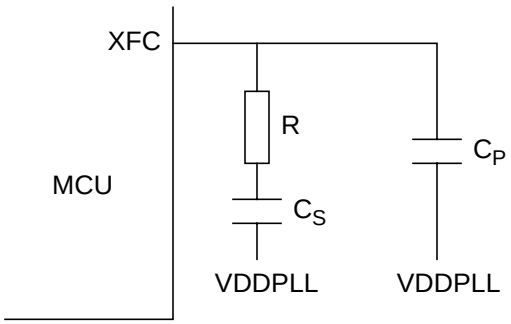

Figure 2-3 PLL Loop Filter Connections

2.3.5 BKGD / $\overline{\text{TAGHI}}$ / MODC — Background Debug, Tag High, and Mode Pin

The BKGD/$\overline{\text{TAGHI}}$/MODC pin is used as a pseudo-open-drain pin for the background debug communication. In MCU expanded modes of operation when instruction tagging is on, an input low on this pin during the falling edge of E-clock tags the high half of the instruction word being read into the instruction queue. It is used as a MCU operating mode select pin during reset. The state of this pin is latched to the MODC bit at the rising edge of $\overline{\text{RESET}}$. This pin has a permanently enabled pull-up device.

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Table 4-3 Voltage Regulator VREGEN

VREGEN	Description
1	Internal Voltage Regulator enabled
0	Internal Voltage Regulator disabled, VDD1,2 and VDDPLL must be supplied externally with 2.5V

4.3 Security

The device will make available a security feature preventing the unauthorized read and write of the memory contents. This feature allows:

- Protection of the contents of FLASH,
- Protection of the contents of EEPROM,
- Operation in single-chip mode, No BDM possible
- Operation from external memory with internal FLASH and EEPROM disabled.

The user must be reminded that part of the security must lie with the user's code. An extreme example would be user's code that dumps the contents of the internal program. This code would defeat the purpose of security. At the same time the user may also wish to put a back door in the user's program. An example of this is the user downloads a key through the SCI which allows access to a programming routine that updates parameters stored in EEPROM.

4.3.1 Securing the Microcontroller

Once the user has programmed the FLASH and EEPROM (if desired), the part can be secured by programming the security bits located in the FLASH module. These non-volatile bits will keep the part secured through resetting the part and through powering down the part.

The security byte resides in a portion of the Flash array.

Check the Flash Block User Guide for more details on the security configuration.

4.3.2 Operation of the Secured Microcontroller

4.3.2.1 Normal Single Chip Mode

This will be the most common usage of the secured part. Everything will appear the same as if the part was not secured with the exception of BDM operation. The BDM operation will be blocked.

4.3.2.2 Executing from External Memory

The user may wish to execute from external space with a secured microcontroller. This is accomplished by resetting directly into expanded mode. The internal FLASH and EEPROM will be disabled. BDM operations will be blocked.

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NOTE: *For devices assembled in 80-pin QFP packages all non-bonded out pins should be configured as outputs after reset in order to avoid current drawn from floating inputs. Refer to* ***Table 2-1*** *for affected pins.*

5.3.2 Memory

Refer to **Table 1-1** for locations of the memories depending on the operating mode after reset.

The RAM array is not automatically initialized out of reset.

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Consult the EETS2K Block User Guide for information about the EEPROM module.

Section 18 RAM Block Description

This module supports single-cycle misaligned word accesses without wait states.

Section 19 MSCAN Block Description

There are three MSCAN modules (CAN4, CAN1 and CAN0) implemented on the MC9S12DT128B. Consult the MSCAN Block User Guide for information about the Motorola Scalable CAN Module.

Section 20 Port Integration Module (PIM) Block Description

Consult the PIM_9DTB128 Block User Guide for information about the Port Integration Module.

Section 21 Voltage Regulator (VREG) Block Description

Consult the VREG Block User Guide for information about the dual output linear voltage regulator.

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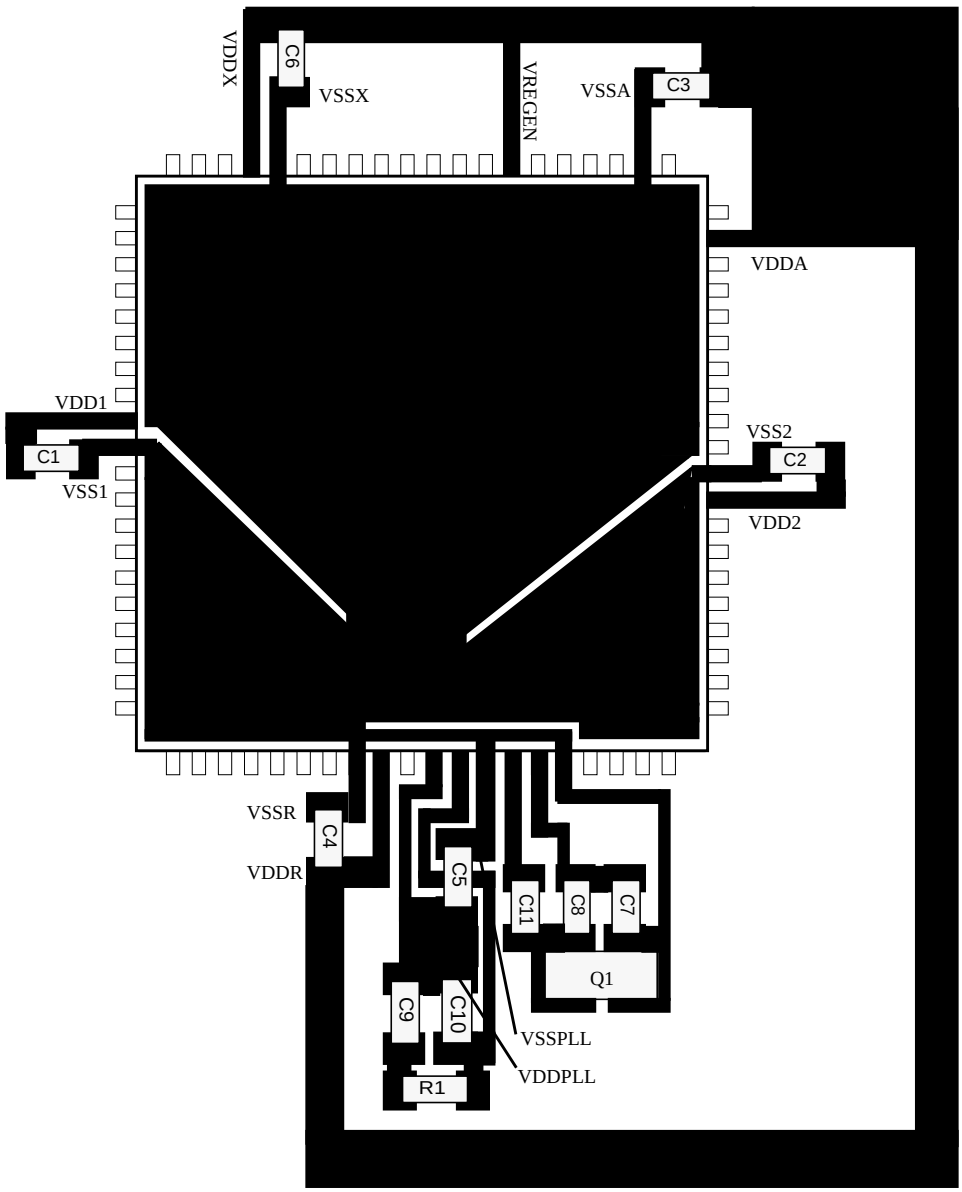
Figure 22-2 Recommended PCB Layout for 80QFP Colpitts Oscillator



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Appendix A Electrical Characteristics

A.1 General

This introduction is intended to give an overview on several common topics like power supply, current injection etc.

A.1.1 Parameter Classification

The electrical parameters shown in this supplement are guaranteed by various methods. To give the customer a better understanding the following classification is used and the parameters are tagged accordingly in the tables where appropriate.

P:

Those parameters are guaranteed during production testing on each individual device.

C:

Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations. They are regularly verified by production monitors.

T:

Those parameters are achieved by design characterization on a small sample size from typical devices. All values shown in the typical column are within this category.

D:

Those parameters are derived mainly from simulations.

A.1.2 Power Supply

The MC9S12DT128B utilizes several pins to supply power to the I/O ports, A/D converter, oscillator and PLL as well as the digital core.

The VDDA, VSSA pair supplies the A/D converter and the resistor ladder of the internal voltage regulator.

The VDDX, VSSX, VDDR and VSSR pairs supply the I/O pins ,VDDR supplies also the internal voltage regulator.

VDD1, VSS1, VDD2 and VSS2 are the supply pins for the digital logic, VDDPLL, VSSPLL supply the oscillator and the PLL.

VSS1 and VSS2 are internally connected by metal.

VDDA, VDDX, VDDR as well as VSSA, VSSX, VSSR are connected by anti-parallel diodes for ESD protection.

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NOTE: *In the following context VDD5 is used for either VDDA, VDDR and VDDX; VSS5 is used for either VSSA, VSSR and VSSX unless otherwise noted.*
IDD5 denotes the sum of the currents flowing into the VDDA, VDDX and VDDR pins.
VDD is used for VDD1, VDD2 and VDDPLL, VSS is used for VSS1, VSS2 and VSSPLL.
IDD is used for the sum of the currents flowing into VDD1 and VDD2.

A.1.3 Pins

There are four groups of functional pins.

A.1.3.1 5V I/O pins

Those I/O pins have a nominal level of 5V. This class of pins is comprised of all port I/O pins, the analog inputs, BKGD pin and the RESET inputs.The internal structure of all those pins is identical, however some of the functionality may be disabled. E.g. for the analog inputs the output drivers, pull-up and pull-down resistors are disabled permanently.

A.1.3.2 Analog Reference

This class is made up by the two VRH and VRL pins.

A.1.3.3 Oscillator

The pins XFC, EXTAL, XTAL dedicated to the oscillator have a nominal 2.5V level. They are supplied by VDDPLL.

A.1.3.4 TEST

This pin is used for production testing only.

A.1.3.5 VREGEN

This pin is used to enable the on chip voltage regulator.

A.1.4 Current Injection

Power supply must maintain regulation within operating V_{DD5} or V_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{in} > V_{DD5}$) is greater than I_{DD5}, the injection current may flow out of VDD5 and could result in external power supply going out of regulation. Insure external VDD5 load will shunt current greater than maximum injection current. This will be the greatest risk when the MCU is not consuming power; e.g. if no system clock is present, or if clock rate is very low which would reduce overall power consumption.

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given. A very good estimate is to take the single chip currents and add the currents due to the external loads.

Table A-7 Supply Current Characteristics

Conditions are shown in **Table A-4** unless otherwise noted							
Num	**C**	**Rating**	**Symbol**	**Min**	**Typ**	**Max**	**Unit**
1	P	Run supply currents Single Chip, Internal regulator enabled	I_{DD5}			55	mA
2	P P	Wait Supply current All modules enabled, PLL on only RTI enabled [1]	I_{DDW}			30 5	mA
3		Pseudo Stop Current (RTI and COP disabled) [1, 2]	I_{DDPS}				µA
	C	-40°C			370		
	P	27°C			400	500	
	C	70°C			450		
	C	85°C			550		
	P	"C" Temp Option 100°C			600	1600	
	C	105°C			650		
	P	"V" Temp Option 120°C			800	2100	
	C	125°C			850		
	P	“M” Temp Option 140°C			1200	5000	
4		Pseudo Stop Current (RTI and COP enabled) [1, 2]	I_{DDPS}				µA
	C	-40°C			570		
	C	27°C			600		
	C	70°C			650		
	C	85°C			750		
	C	105°C			850		
	C	125°C			1200		
	C	140°C			1500		
5		Stop Current [2]	I_{DDS}				µA
	C	-40°C			12		
	P	27°C			25	100	
	C	70°C			100		
	C	85°C			130		
	P	"C" Temp Option 100°C			160	1200	
	C	105°C			200		
	P	"V" Temp Option 120°C			350	1700	
	C	125°C			400		
	P	“M” Temp Option 140°C			600	5000	

NOTES:
1. PLL off, Oscillator in Colpitts Mode
2. At those low power dissipation levels $T_J = T_A$ can be assumed

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A.3.1.3 Sector Erase

Erasing a 512 byte Flash sector or a 4 byte EEPROM sector takes:

$$t_{era} \approx 4000 \cdot \frac{1}{f_{NVMOP}}$$

The setup times can be ignored for this operation.

A.3.1.4 Mass Erase

Erasing a NVM block takes:

$$t_{mass} \approx 20000 \cdot \frac{1}{f_{NVMOP}}$$

The setup times can be ignored for this operation.

A.3.1.5 Blank Check

The time it takes to perform a blank check on the Flash or EEPROM is dependant on the location of the first non-blank word starting at relative address zero. It takes one bus cycle per word to verify plus a setup of the command.

$$t_{check} \approx location \cdot t_{cyc} + 10 \cdot t_{cyc}$$

Table A-11 NVM Timing Characteristics

Conditions are shown in **Table A-4** unless otherwise noted							
Num	**C**	**Rating**	**Symbol**	**Min**	**Typ**	**Max**	**Unit**
1	D	External Oscillator Clock	f_{NVMOSC}	0.5		50 [1]	MHz
2	D	Bus frequency for Programming or Erase Operations	f_{NVMBUS}	1			MHz
3	D	Operating Frequency	f_{NVMOP}	150		200	kHz
4	P	Single Word Programming Time	t_{swpgm}	46 [2]		74.5 [3]	µs
5	D	Flash Burst Programming consecutive word [4]	t_{bwpgm}	20.4 [2]		31 [3]	µs
6	D	Flash Burst Programming Time for 32 Words [4]	t_{brpgm}	678.4 [2]		1035.5 [3]	µs
7	P	Sector Erase Time	t_{era}	20 [5]		26.7 [3]	ms
8	P	Mass Erase Time	t_{mass}	100 [5]		133 [3]	ms
9	D	Blank Check Time Flash per block	t_{check}	11 [6]		32778 [7]	t_{cyc}
10	D	Blank Check Time EEPROM per block	t_{check}	11 [6]		2058 [7]	t_{cyc}

NOTES:
1. Restrictions for oscillator in crystal mode apply!
2. Minimum Programming times are achieved under maximum NVM operating frequency f_{NVMOP} and maximum bus frequency f_{bus}.
3. Maximum Erase and Programming times are achieved under particular combinations of f_{NVMOP} and bus frequency f_{bus}. Refer to formulae in Sections **A.3.1.1 - A.3.1.5** for guidance.

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A.5 Reset, Oscillator and PLL

This section summarizes the electrical characteristics of the various startup scenarios for Oscillator and Phase-Locked-Loop (PLL).

A.5.1 Startup

Table A-14 summarizes several startup characteristics explained in this section. Detailed description of the startup behavior can be found in the Clock and Reset Generator (CRG) Block User Guide.

Table A-14 Startup Characteristics

Conditions are shown in **Table A-4** unless otherwise noted							
Num	**C**	**Rating**	**Symbol**	**Min**	**Typ**	**Max**	**Unit**
1	T	POR release level	V_{PORR}			2.07	V
2	T	POR assert level	V_{PORA}	0.97			V
3	D	Reset input pulse width, minimum input time	PW_{RSTL}	2			t_{osc}
4	D	Startup from Reset	n_{RST}	192		196	n_{osc}
5	D	Interrupt pulse width, $\overline{IRQ}$ edge-sensitive mode	PW_{IRQ}	20			ns
6	D	Wait recovery startup time	t_{WRS}			14	t_{cyc}

A.5.1.1 POR

The release level V_{PORR} and the assert level V_{PORA} are derived from the V_{DD} Supply. They are also valid if the device is powered externally. After releasing the POR reset the oscillator and the clock quality check are started. If after a time t_{CQOUT} no valid oscillation is detected, the MCU will start using the internal self clock. The fastest startup time possible is given by n_{uposc}.

A.5.1.2 SRAM Data Retention

Provided an appropriate external reset signal is applied to the MCU, preventing the CPU from executing code when VDD5 is out of specification limits, the SRAM contents integrity is guaranteed if after the reset the PORF bit in the CRG Flags Register has not been set.

A.5.1.3 External Reset

When external reset is asserted for a time greater than PW_{RSTL} the CRG module generates an internal reset, and the CPU starts fetching the reset vector without doing a clock quality check, if there was an oscillation before reset.

A.5.1.4 Stop Recovery

Out of STOP the controller can be woken up by an external interrupt. A clock quality check as after POR is performed before releasing the clocks to the system.

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A.6 MSCAN

Table A-17 MSCAN Wake-up Pulse Characteristics

Conditions are shown in **Table A-4** unless otherwise noted							
Num	**C**	**Rating**	**Symbol**	**Min**	**Typ**	**Max**	**Unit**
1	P	MSCAN Wake-up dominant pulse filtered	t_{WUP}			2	µs
2	P	MSCAN Wake-up dominant pulse pass	t_{WUP}	5			µs

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A.8 External Bus Timing

A timing diagram of the external multiplexed-bus is illustrated in **Figure A-9** with the actual timing values shown on table **Table A-20**. All major bus signals are included in the diagram. While both a data write and data read cycle are shown, only one or the other would occur on a particular bus cycle.

A.8.1 General Muxed Bus Timing

The expanded bus timings are highly dependent on the load conditions. The timing parameters shown assume a balanced load across all outputs.

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Appendix B Package Information

B.1 General

This section provides the physical dimensions of the MC9S12DT128B packages.

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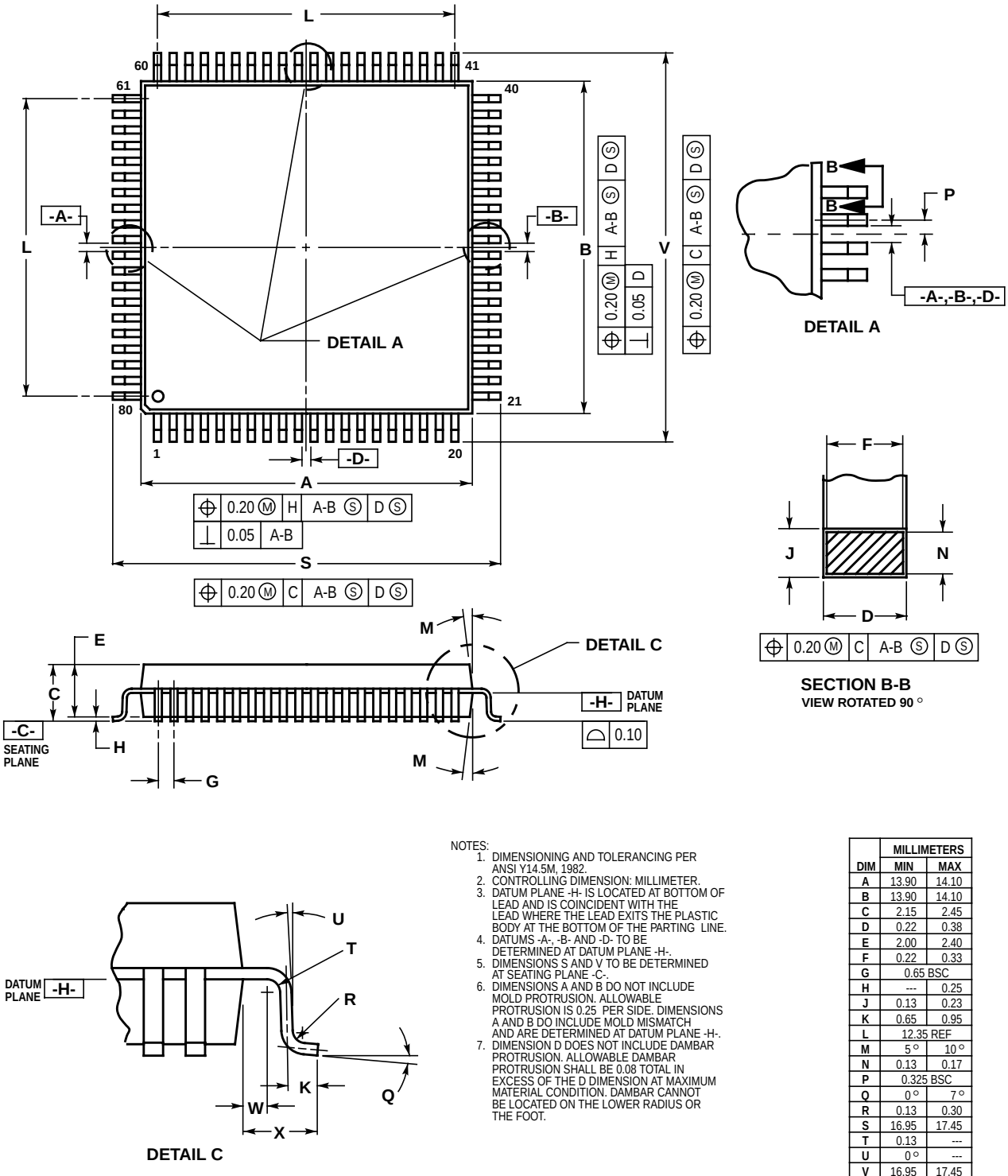
B.3 80-pin QFP package



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DATUM PLANE -H- IS LOCATED AT BOTTOM OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE BOTTOM OF THE PARTING LINE.
4. DATUMS -A-, -B- AND -D- TO BE DETERMINED AT DATUM PLANE -H-.
5. DIMENSIONS S AND V TO BE DETERMINED AT SEATING PLANE -C-.
6. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.25 PER SIDE. DIMENSIONS A AND B DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -H-.
7. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT.

	MILLIMETERS	
DIM	MIN	MAX
A	13.90	14.10
B	13.90	14.10
C	2.15	2.45
D	0.22	0.38
E	2.00	2.40
F	0.22	0.33
G	0.65 BSC	
H	---	0.25
J	0.13	0.23
K	0.65	0.95
L	12.35 REF	
M	5°	10°
N	0.13	0.17
P	0.325 BSC	
Q	0°	7°
R	0.13	0.30
S	16.95	17.45
T	0.13	---
U	0°	---
V	16.95	17.45
W	0.35	0.45
X	1.6 REF	

Figure 1 80-pin QFP Mechanical Dimensions (case no. 841B)

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